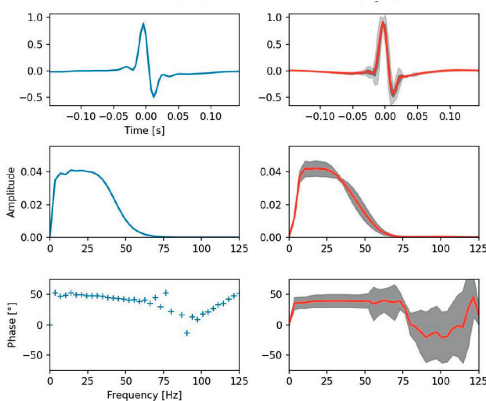


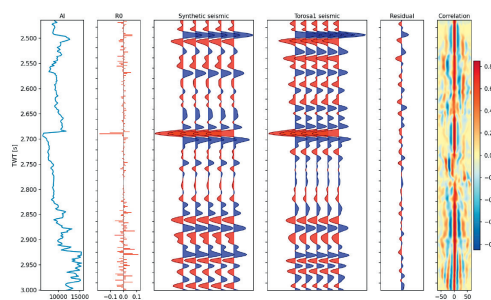
Automated Well-tie

DLseis/Research Consortium

- Automated wavelet extraction using Deep Neural Network technology
- Bayesian search for multi-dimensional parameter optimisation
- Best fit plus uncertainty estimates



Wavelet found by DNN (right), true wavelet (left)



Well-tie by DNN wavelet extraction and Bayesian search strategy

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